

Special Issue

Design of Fault Tolerant Digital Circuits and Systems

Message from the Guest Editor

With technology scaling down into the nanometer scale, the impact of variations in manufacturing or the environment on digital circuits and system has significantly enlarged. As a result, circuit operation has become uncertain and highly likely to experience malfunctions. This Special Issue intends to present novel designs that make digital circuits and systems tolerant to faults or errors. Subjects covered in this Special Issue include, but are not limited to, design innovations in devices, circuits, systems, architecture, algorithms or test methodology, able to improve fault tolerance.

Guest Editor

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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